

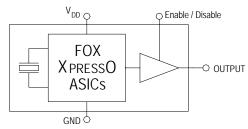
LVDS 3.2 x 2.5mm 2.5V Oscillator

Model: FXO-LC32 SERIES

Freq: 0.75 MHz to 1.0GHz

Features

- XTREMELY Low Jitter
- Low Cost
- XPRESS Delivery
- Frequency Resolution to six decimal places
- Stabilities to ± 25 PPM
- -20 to +70°C or -40 to +85°C operating temperatures
- Tri-State Enable / Disable Feature
- Industry Standard Package, Footprint & Pin-Out
- Fully RoHS and REACH compliant
- Gold over Nickel Termination Finish
- Serial ID with Comprehensive Traceability



For more information -- Click on the drawing

Description

The Fox XPRESSO Crystal Oscillator is a breakthrough in configurable Frequency Control Solutions. XPRESSO utilizes a family of proprietary ASICs, designed and developed by Fox, with a key focus on noise reduction technologies.

The 3rd order Delta Sigma Modulator reduces noise to the levels that are comparable to traditional Bulk Quartz and SAW oscillators. The ASICs family has ability to select the output type, input voltages, and temperature performance features.

With the XPRESS lead-time, low cost, low noise, wide frequency range, excellent ambient performance, XpressO is an excellent choice over the conventional technologies.









Applications

- · ANY application requiring an oscillator
- SONET
- Ethernet
- Storage Area Network
- Broadband Access
- Microprocessors / DSP / FPGA
- Industrial Controllers
- Test and Measurement Equipment
- Fiber Channel

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FÖX



Model Selection Guide & Fox Part Number

STEP #1: Customer selects the Model Description and provides to Fox Customer Service

Model Description

H = HCMOS

C = Ceramic

3 = 3.3 V

0 = ± 100 PPM

blank = -20°C to +70°C

L = LVDS

O = Quartz

 $3 = 3.2 \times 2.5 \text{mm}$ 2 = 2

2 = 2.5 V $5 = \pm 50 \text{ PPM}$

 $R = -40^{\circ}C \text{ to } +85^{\circ}C$

P = LVPECL

 $5 = 5 \times 3.2$ mm

 $7 = 7 \times 5 \text{mm}$

 $6 = \pm 25 \text{ PPM } (-20 \sim +70^{\circ}\text{C})$

M = LVDS (pin 2 E/D)

Q = LVPECL (pin 2 E/D) $X = HCMOS (comp 2^{nd} Output)$

STEP #2: The Fox Customer Service team provides a customer specific Part Number for use on their Bill Of Materials (BOM).

Fox Part Number (The assigned Fox Part Number must be on the BOM – not the above Model Description) (This will ensure receipt of the proper part)

769A - 622.08 - 2

The 1st Field
Product Code #
769A = FXO-LC32

769 = FXO-LC33

770B = FXO-LC52 770 = FXO-LC53

770C = FXO-MC52 770A = FXO-MC53 The 2nd Field

The Customer's Frequency

The 3¹⁰ Field

Fox Internally Generated Number (If any specification changes, the last digits change) (The same specs for a different customer also changes the last digits)

This example, FXO-LC325R-622.08 = LVDS Output, Ceramic, 3.2 x 2.5mm Package, 2.5V, ±50 PPM Stability, -40 to +85°C Temperature Range, at 622.08 MHz





Electrical Characteristics				
Parameters	Symbol	Condition	Maximum Value (unless otherwise noted)	
Frequency Range	Fo		0.750 MHz to 1.0 GHz	
Frequency Stability ¹		0.75 ~ 630.000 MHz (-20 to +70°C) 0.75 ~ 630.000 MHz (-40 to +85°C) 630.000+ MHz ~ 1.000 GHz (-20 to +70°C) 630.000+ MHz ~ 1.000 GHz (-40 to +85°C)	100, 50, 25* PPM 100, 50 PPM 100, 50 PPM 100 PPM	
Temperature Range	T _O	Standard operating Optional operating Storage	-20°C to +70°C -40°C to +85°C -55°C to +125°C	
Supply Voltage	V_{DD}	Standard	2.5V ± 5%	
Input Current (@ 100 Ohm LOAD)	I _{DD}	0.75 ~ 20.000 MHz 20.000+ ~ 220.000 MHz 220.000+ ~ 630.000 MHz 630.000+ MHz ~ 1.000 GHz	26 mA 34 mA 44 mA 65 mA	
Output Load		Standard	100 Ohms Typ.	
Start-Up Time	Ts		10 mS	
Output Enable / Disable Time			100 nS	
Moisture Sensitivity Level	MSL	JEDEC J-STD-20	1	
Termination Finish			Au	

¹Inclusive of 25°C tolerance, operating temperature range, input voltage change, load change, aging, shock and vibration. *Excludes aging.

Absolute	Maximu	ım Rat	ings
(Useful life may	be impaired.	For user go	uidelines

(Useful life may be impaired. For user guidelines only, not tested.

Operation is only guaranteed for voltage and temperature specifications in Electrical Characteristics section.)

Parameters	Symbol	Condition	Maximum Value (unless otherwise noted)
Input Voltage	V_{DD}		-0.5V to +5.0V
Operating Temperature	T _{AMAX}		–55°C to +105°C
Storage Temperature	T _{STG}		–55°C to +125°C
Junction Temperature			150°C
ESD Sensitivity	HBM	Human Body Model	> 1 kV

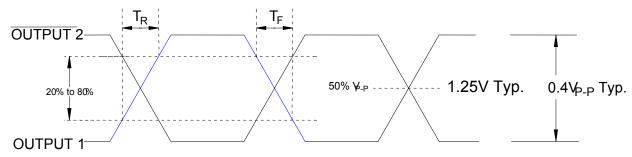




Output Wave Characteristics					
Parameters	Symbol	Condition	Maximum Value (unless otherwise noted)		
Differential Output Voltage	V _{OD}	0.75 MHz to 1.0 GHz	0.4V Typ.		
Output Offset Voltage	Vos	Volts DC	1.25V Typ		
Output Symmetry (See Drawing Below)		@ 50% V _{P-P} Level	45% ~ 55%		
Output Enable (PIN # 1) Voltage Note1	V _{IH}		≥ 70% V _{DD}		
Output Disable (PIN # 1) Voltage Note1	V_{IL}		≤ 30% V _{DD}		
Cycle Rise Time (See Drawing Below)	T _R	20%~80% Vp-p	400 pS		
Cycle Fall Time (See Drawing Below)	T _F	80%~20% Vp-p	400 pS		

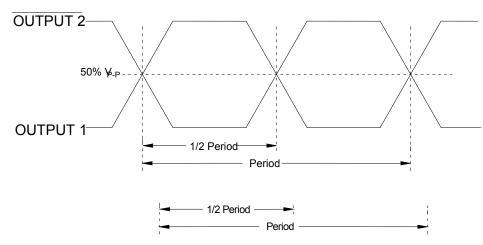
Note1 An optional PIN # 2 as Enable / Disable is available – see Model Selection Guide (page 2)

Rise Time / Fall Time Measurements



Oscillator Symmetry

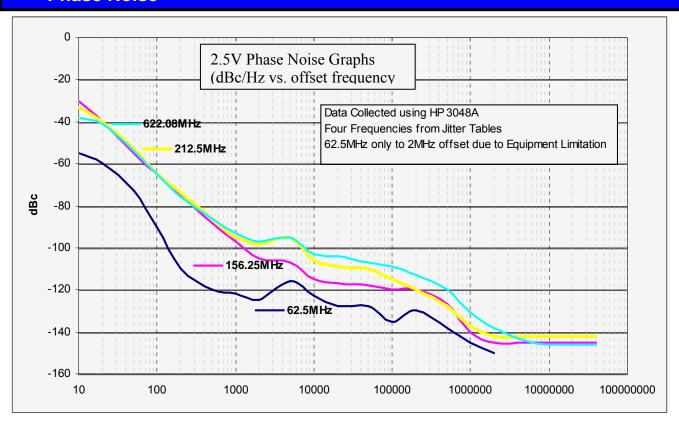
Ideally, Symmetry should be 50/50 for 1/2 period -- Other expressions are 45/55 or 55/45



FÖX



Phase Noise



Jitter is frequency dependent. Below are typical values at select frequencies.

LVDS Phase	e Jitter & Time Inte	erval Error (TIE)	
Frequency	Phase Jitter (12kHz to 20MHz)	TIE (Sigma of Jitter Distribution)	Units
62.5 MHz	0.9	2.9	pS RMS
156.25 MHz	1.1	3.5	pS RMS
212.5 MHz	1.2	3.9	pS RMS
622.08MHz	0.8	2.4	pS RMS

Phase Jitter is integrated from HP3048 Phase Noise Measurement System; measured directly into 50 ohm input; V_{DD} = 2.5V.

TIE was measured on LeCroy LC684 Digital Storage Scope, directly into 50 ohm input, with Amherst M1 software; V_{DD} = 2.5V.

Per MJSQ spec (Methodologies for Jitter and Signal Quality specifications)

LVDS Random & Deterministic Jitter Composition					
Frequency	Random (Rj) (pS RMS)	Deterministic (Dj)	Total Jitter (Tj) (14 x Rj) + Dj		
62.5 MHz	1.3	9.6	28.6 pS		
156.25 MHz	1.4	9.8	29.4pS		
212.5 MHz	1.4	11.4	30.9 pS		
622.08 MHz	1.0	13.05	27.5 pS		

Rj and Dj, measured on LeCroy LC684 Digital Storage Scope, directly into 50 ohm input, with Amherst M1 software.

Per MJSQ spec (Methodologies for Jitter and Signal Quality specifications)

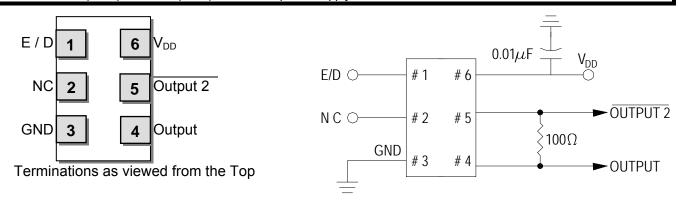




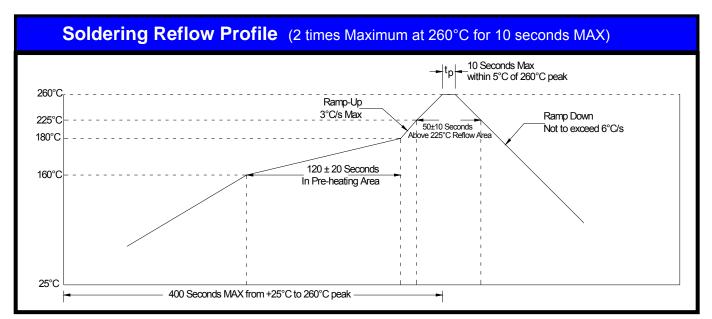
Pin	Pin Description and Recommended Circuit				
Pin#	Name	Type	Function		
1	E/D ¹	Logic	Enable / Disable Control of Output (0 = Disabled)		
2	NC		No Connection – Leave OPEN		
3	GND	Ground	Electrical Ground for V _{DD}		
4	Output	Output	LVDS Oscillator Output		
5	Output 2	Output	Complementary LVDS Output		
6	V _{DD} ²	Power	Power Supply Source Voltage		

NOTES:

- ¹ Includes pull-up resistor to V_{DD} to provide output when the pin (1) is No Connect.
- ² Installation should include a 0.01μF bypass capacitor placed between V_{DD} (Pin 6) and GND (Pin 3) to minimize power supply line noise.



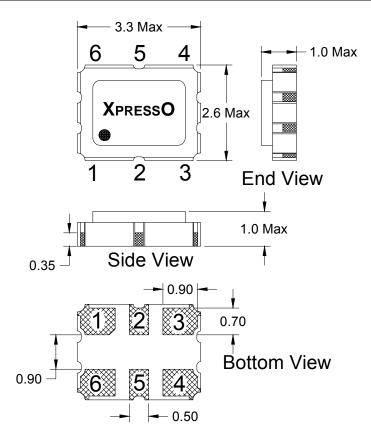
Enable / Disable Control		
Pin # 1 (state)	Output (Pin # 4, Pin # 5)	
OPEN (No Connection)	ACTIVE Output	
"1" Level V _{IH} ≥ 70% V _{DD}	ACTIVE Output	
"0" Level V _{IL} ≤ 30% V _{DD}	High Impedance	







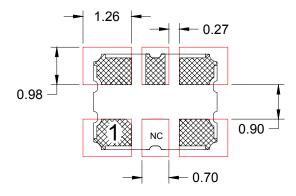
Mechanical Dimensional Drawing & Pad Layout



Actual part marking is depicted.

See **Traceability** (pg. 9) for more information

Recommended Solder Pad Layout



Pin Connections

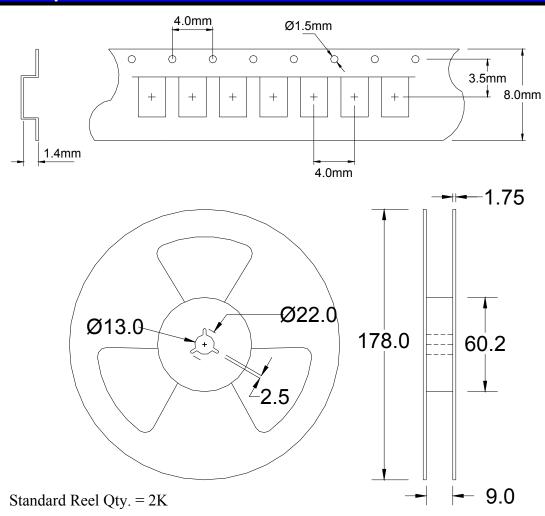
#1 E/D #4 V_{OUT 1} #2 N.C. #5 V_{OUT 2} #3 GND #6 V_{DD}

Drawing is for reference to critical specifications defined by size measurements. Certain non-critical visual attributes, such as side castellations, reference pin shape, etc. may vary





Tape and Reel Dimensions



Labeling (Reels and smaller packaging are labeled with the below)



An additional identification code is contained internally if tracking should ever be necessary





Traceability - LOT Number & Serial Identification

LOT Number

The LOT Number has direct ties to the customer purchase order. The LOT Number is marked on the "Reel" label, and also stored internally on non-volatile memory inside the XPRESSO part. XPRESSO parts that are shipped Tape and Reel, are also placed in an Electro Static Discharge (ESD) bag and will have the LOT Number labeled on the exterior of the ESD bag.

It is recommended that the XPRESSO parts remain in this ESD bag during storage for protection and identification.

If the parts become separated from the label showing the LOT Number, it can be retrieved from inside one of the parts, and the information that can be obtained is listed below:

- Customer Purchase Order Number
- Internal Fox Sales Order Number
- Dates that the XPRESSO part was shipped from the factory
- The assigned customer part number
- The specification that the part was designed for

Serial Identification

The Serial ID is the individualized information about the configuration of that particular XPRESSO part. The Serial ID is unique for each and every XPRESSO part, and can be read by special Fox equipment.

With the Serial ID, the below information can be obtained about that individual, XPRESSO part:

- Equipment that the XPRESSO part was configured on
- Raw material used to configure the XPRESSO part
- Traceability of the raw material back to the foundries manufacturing lot
- Date and Time that the part was configured
- Any optimized electrical parameters based on customer specifications
- Electrical testing of the actual completed part
- Human resource that was monitoring the configuration of the part

Fox has equipment placed at key Fox locations World Wide to read the Lot Identification and Serial Number of any XPRESSO part produced and can then obtain the information from above within 24 hours





Party (SGS) Material Report



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FOX ELECTRONICS

5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA

The following sample(s) was/were submitted and identified by/on behalf of the client as:

Sample Description : XPRESSO CERAMIC OSCILLATORS Style/Item No. : SEAM SEAL CLOCK OSCILLATOR

Buyer/Order No. : 47454 : 2008/06/12 Sample Receiving Date

Testing Period : 2008/06/12 TO 2008/06/19

Test Result(s) Please refer to next page(s).

Chenyu Kung / Operation Manager Signed for and on behalf of SGS TAIWAN LTD.

Chemical Laboratory - Taipei

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Party (SGS) Material Report (continued)



Test Report No.: CE/2008/63138 Date: 2008/06/19 Page: 2 of 4

FOX ELECTRONICS

5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA

Test Result(s)

PART NAME NO.1 : MIXED ALL PARTS

Test Item (s):	Unit	Method	MDL	Result
rest item (s):	Unit	Metriod	MDL	No.1
Cadmium (Cd)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Cadmium by ICP-AES.	2	n.d.
Lead (Pb)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Lead by ICP-AES.	2	n.d.
Mercury (Hg)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Mercury by ICP-AES.	2	n.d.
Hexavalent Chromium Cr(VI) by alkaline extraction	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Hexavalent Chromium for non- metallic samples by UV/Vis Spectrometry.	2	n.d.
Halogen	1444	With reference to BS EN 14582:2007. Analysis was performed by IC method for F; CI; Br, I content.	202	2123
Halogen-Fluorine (F) (CAS No.: 007782-41-4)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Fluorine content.	50	n.d.
Halogen-Chlorine (CI) (CAS No.: 007782-50-5)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Chlorine content.	50	n.d.
Halogen-Bromine (Br) (CAS No.: 007726-95-6)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Bromine content.	50	n.d.
Halogen-lodine (I) (CAS No.: 007553-56-2)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for lodine content.	50	n.d.

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Party (SGS) Material Report (continued)



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FOX ELECTRONICS

5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA

Test Item (s):	Unit	Method	MDI	Result
10.73	Oilit	Metrod	MDL	No.1
Sum of PBBs			27	n.d.
Monobromobiphenyl	1	I T	No	n.d.
Dibromobiphenyl	1 1	I T	5	n.d.
Tribromobiphenyl	1	Г	5	n.d.
Tetrabromobiphenyl	1	l f	5	n.d.
Pentabromobiphenyl	1	l T	5	n.d.
Hexabromobiphenyl	1	I T	5	n.d.
Heptabromobiphenyl	1	Ι	5	n.d.
Octabromobiphenyl	1		5	n.d.
Nonabromobiphenyl	1	l T	5	n.d.
Decabromobiphenyl	1	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of PBB and PBDE by GC/MS.	5	n.d.
Sum of PBDEs (Mono to Nona)	mg/kg		4	n.d.
Monobromodiphenyl ether			5	n.d.
Dibromodiphenyl ether	1		5	n.d.
Tribromodiphenyl ether	1		5	n.d.
Tetrabromodiphenyl ether	1	I T		n.d.
Pentabromodiphenyl ether	1	l T		n.d.
Hexabromodiphenyl ether	1	l t	5	n.d.
Heptabromodiphenyl ether	1	l T	5	n.d.
Octabromodiphenyl ether	1 1	l t	5	n.d.
Nonabromodiphenyl ether			5	n.d.
Decabromodiphenyl ether	1	l t	5	n.d.
Sum of PBDEs (Mono to Deca)	1 I	l t	99	n.d.

Note: 1. mg/kg = ppm

2. n.d. = Not Detected

3. MDL = Method Detection Limit

4. "---" = Not Conducted

5. " - " = Not Regulated

6. The sample(s) was/were analyzed on behalf of the applicant as mixing sample in one testing. The above result(s) was/were only given as the informality value.

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Party (SGS) Material Report (continued)



Test Report No.: CE/2008/63138 Date: 2008/06/19 Page: 4 of 4

FOX ELECTRONICS 5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA



** End of Report **

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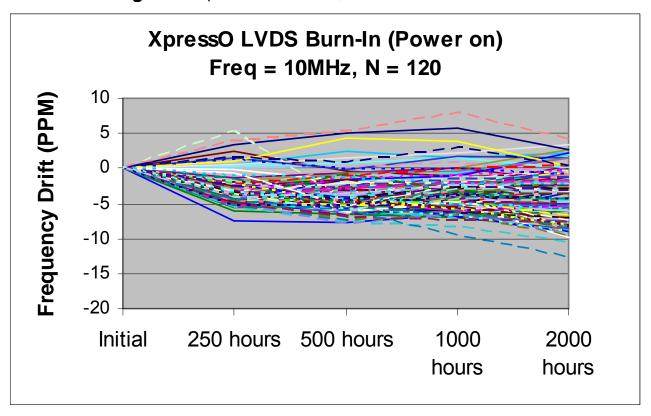


Mechanical Testing

Parameter	Test Method
Mechanical Shock	Drop from 75cm to hardwood surface – 3 times
Mechanical Vibration	10~55Hz, 1.5mm amplitude, 1 Minute Sweep 2 Hours each in 3 Directions (X, Y, Z)
High Temperature Burn-in	Under Power @ 125°C for 2000 Hours (results below)
Hermetic Seal	He pressure: 4 ±1 kgf / cm ² 2 Hour soak

2,000 Hour Burn-In

Burn-In Testing – under power 2000 Hours, 125°C







MTTF / FITS Calculations

Products are grouped together by process for MTTF calculations. (All XpressO output and package types are manufactured with the same process)

Number of Parts Tested: 360 (120 of each output type: HCMOS, LVDS, LVPECL)

Number of Failures: 0 Test Temperature: 125°C Number of Hours: 2000

MTTF was calculated using the following formulas:

[1.] Device Hours (*devhrs*) = (number of devices) x (hours at elevated temperature in °K)

[2.]
$$MTTF = \frac{devhrs \times af \times 2}{\chi^2}$$

[3.] FITS =
$$\frac{1}{MTTF}$$
 * 10⁹

Where:

vvnere:		
Label	Name	Formula/Value
af	Acceleration Factor	$e^{(rac{eV}{k}) imes(rac{1}{t_1}-rac{1}{t_2})}$
eV	Activation Energy	0.40 V
k	Bolzman's Constant	8.62 X 10 ⁻⁵ eV/°K
t ₁		Operating Temperature (°K)
t_2		Accelerated Temperature (°K)
Θ	Theta	Confidence Level (60% industry standard)
r	Failures	Number of failed devices
χ²	Chi-Square	statistical significance for bivariate tabular analysis [table look-up] based on assumed Θ (Theta – confidence) and number of failures (r) For zero failures (60% Confidence): $\chi^2 = 1.830$

DEVICE-HOURS = 360 x 2000 HOURS = 720,000

ACCELERATION FACTOR =
$$e^{(\frac{0.40}{8.625})\times(\frac{1}{298}-\frac{1}{398})}$$
 = 49.91009

MTTF =
$$\frac{720,000 \times 49.91009 \times 2}{1.833}$$
 = 39,209,238 Hours

Failure Rate =
$$\frac{1.833}{720,000 \times 49.91009 \times 2}$$
 = 2.55E-8

FITS = Failure Rate *1E9 = 26





Notes:

Patent Numbers:

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The above specifications, having been carefully prepared and checked, is believed to be accurate at the time of publication; however, no responsibility is assumed by Fox Electronics for inaccuracies.

